

Bayesian Burn-in Procedures for LFPs with the Mixed Binomial Prior Distribution for the Number of Defectives

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abstract

Burn-in procedures are developed for limited failure populations in which defective products fail soon after they are put in operation and non-defective ones never fail during the technological life of the products. The situation where products are produced from a production process with variable fraction defective is considered. Burn-in schemes guaranteeing pre-specified outgoing quality of products are derived using the mixed binomial prior distribution for the number of defectives in a batch.

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